

Resource Summary Report

Generated by NIF on Sep 22, 2026

FEI: ELITE System for Semiconductors

RRID:SCR_019891

Type: Tool

Proper Citation

FEI: ELITE System for Semiconductors (RRID:SCR_019891)

Resource Information

URL: <https://www.fei.com/products/efa/elite-for-semiconductors/>

Proper Citation: FEI: ELITE System for Semiconductors (RRID:SCR_019891)

Description: Semiconductor with enhanced lock in thermal emission that provides better signal to noise ratio, increased sensitivity and higher feature resolution than steady state thermography.

Resource Type: instrument resource

Keywords: FEI, EFA System, Instrument, Equipment, USEDit,

Availability: Commercially available

Resource Name: FEI: ELITE System for Semiconductors

Resource ID: SCR_019891

Alternate IDs: Model_Number_ELITE

Record Creation Time: 20220129T080347+0000

Record Last Update: 20260919T195420+0000

Ratings and Alerts

No rating or validation information has been found for FEI: ELITE System for Semiconductors.

No alerts have been found for FEI: ELITE System for Semiconductors.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.